### 2.5V/3.3V DIFFERENTIAL LVPECL 1:9 CLOCK DISTRIBUTION BUFFER AND CLOCK DRIVER

The MC100ES6226 is a bipolar monolithic differential clock distribution buffer and clock divider. Designed for most demanding clock distribution systems, the MC100ES6226 supports various applications requiring a large number of outputs to drive precisely aligned clock signals. Using SiGe technology and a fully differential architecture, the device offers superior digital signal characteristics and very low clock skew error. Target applications for this clock driver are high performance clock distribution systems for computing, networking and telecommunication systems.

## Features

- Fully differential architecture from input to all outputs
- SiGe technology supports near-zero output skew
- Selectable 1:1 or 1:2 frequency outputs
- LVPECL compatible differential clock inputs and outputs
- LVCMOS compatible control inputs
- Single 3.3 V or 2.5 V supply
- Max. 35 ps maximum output skew (within output bank)
- Max. 50 ps maximum device skew
- Supports DC operation and up to 3 GHz (typ.) clock signals
- Synchronous output enable eliminating output runt pulse generation and metastability
- Standard 32-lead LQFP package
- Industrial temperature range
- 32-lead Pb -free package available


## Functional Description

MC100ES6226 is designed for very skew critical differential clock distribution systems and supports clock frequencies from DC up to 3.0 GHz . Typical applications for the MC100ES6226 are primary clock distribution systems on backplanes of high-performance computer, networking and telecommunication systems, as well as on-board clocking of OC-3, OC-12 and OC-48 speed communication systems.

The MC100ES6226 can be operated from a 3.3 V or 2.5 V positive supply without the requirement of a negative supply line. Each of the output banks of three differential clock output pairs may be independently configured to distribute the input frequency or half of the input frequency. The FSEL0 and FSEL1 clock frequency selects are asychronous control inputs. Any changes of the control inputs require a MR pulse for resynchronization of the $\div 2$ outputs.


Figure 1. MC100ES6226 Logic Diagram


Figure 2. 32-Lead Package Pinout (Top View)

Table 1. Pin Configuration

| Pin | I/O | Type | Function |
| :---: | :---: | :---: | :---: |
| CLK, $\overline{\text { CLK }}$ | Input | LVPECL | Differential reference clock signal input |
| $\overline{\mathrm{OE}}$ | Input | LVCMOS | Output enable |
| MR | Input | LVCMOS | Device reset |
| FSEL0, FSEL1 | Input | LVCMOS | Output frequency divider select |
| $\begin{aligned} & \text { QA[0-2], } \overline{\mathrm{QA}[0-2]} \\ & \text { QB[0-2], } \overline{\mathrm{QB}[0-2]} \\ & \text { QC[0-2], } \overline{\mathrm{QC}[0-2]} \end{aligned}$ | Output | LVPECL | Differential clock outputs (banks A, B and C) |
| GND | Supply | GND | Negative power supply |
| $\mathrm{V}_{\text {CC }}$ | Supply | $\mathrm{V}_{\text {CC }}$ | Positive power supply. All $\mathrm{V}_{\mathrm{CC}}$ pins must be connected to the positive power supply for correct DC and AC operation |

Table 2. Function Table

| Control | Default | 0 | 1 |
| :---: | :---: | :---: | :---: |
| $\overline{\mathrm{OE}}$ | 0 | $\mathrm{Qx}[0-2], \overline{\mathrm{Qx}[0}-\overline{2]}$ are active. Deassertion of $\overline{\mathrm{OE}}$ can be asynchronous to the reference clock without generation of output runt pulses | $\mathrm{Qx}[0-2]=\mathrm{L}, \overline{\mathrm{Qx}[0}-\overline{2]}=\mathrm{H}$ (outputs disabled). Assertion of $\overline{\mathrm{OE}}$ can be asynchronous to the reference clock without generation of output runt pulses |
| MR | 0 | Normal operation | Device reset (asynchronous) |
| FSEL0, FSEL1 | 00 | See Table 3 |  |

Table 3. Output Frequency Select Control

| FSEL0 | FSEL1 | QA0 to QA2 | QB0 to QB2 | QC0 to QC2 |
| :---: | :---: | :---: | :---: | :---: |
| 0 | 0 | $\mathrm{f}_{\mathrm{QAO}: 2}=\mathrm{f}_{\mathrm{CLK}}$ | $\mathrm{f}_{\mathrm{QBO}: 2}=\mathrm{f}_{\mathrm{CLK}}$ | $\mathrm{f}_{\mathrm{QCO}: 2}=\mathrm{f}_{\mathrm{CLK}}$ |
| 0 | 1 | $\mathrm{f}_{\mathrm{QAO}: 2}=\mathrm{f}_{\mathrm{CLK}}$ | $\mathrm{f}_{\mathrm{QBO}: 2}=\mathrm{f}_{\mathrm{CLK}}$ | $\mathrm{f}_{\mathrm{QCO}: 2}=\mathrm{f}_{\mathrm{CLK}} \div 2$ |
| 1 | 0 | $\mathrm{f}_{\mathrm{QAO}: 2}=\mathrm{f}_{\mathrm{CLK}}$ | $\mathrm{f}_{\mathrm{QBO}: 2}=\mathrm{f}_{\mathrm{CLK}} \div 2$ | $\mathrm{f}_{\mathrm{QCO}: 2}=\mathrm{f}_{\mathrm{CLK}} \div 2$ |
| 1 | 1 | $\mathrm{f}_{\mathrm{QAO}: 2}=\mathrm{f}_{\mathrm{CLK}} \div 2$ | $\mathrm{f}_{\mathrm{QBO}: 2}=\mathrm{f}_{\mathrm{CLK}} \div 2$ | $\mathrm{f}_{\mathrm{QCO}: 2}=\mathrm{f}_{\mathrm{CLK}} \div 2$ |

Table 4. Absolute Maximum Ratings ${ }^{(1)}$

| Symbol | Characteristics | Min | Max | Unit | Condition |
| :---: | :--- | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply Voltage | -0.3 | 3.6 | V |  |
| $\mathrm{~V}_{\text {IN }}$ | DC Input Voltage | -0.3 | $\mathrm{~V}_{\mathrm{CC}}+0.3$ | V |  |
| $\mathrm{~V}_{\text {OUT }}$ | DC Output Voltage | -0.3 | $\mathrm{~V}_{\mathrm{CC}}+0.3$ | V |  |
| $\mathrm{I}_{\mathrm{IN}}$ | DC Input Current |  | $\pm 20$ | mA |  |
| $\mathrm{I}_{\text {OUT }}$ | DC Output Current |  |  | $\pm 50$ | mA |
| $\mathrm{~T}_{\text {S }}$ | Storage Temperature | -65 | 125 | ${ }^{\circ} \mathrm{C}$ |  |

1. Absolute maximum continuous ratings are those maximum values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those indicated may adversely affect device reliability. Functional operation at absolute-maximum-rated conditions is not implied.

Table 5. General Specifications

| Symbol | Characteristics | Min | Typ | Max | Unit | Condition |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{TT}}$ | Output Termination Voltage |  | $\mathrm{V}_{\mathrm{CC}}-2^{(1)}$ |  | V |  |
| MM | ESD Protection (Machine Model) | 300 |  |  | V |  |
| HBM | ESD Protection (Human Body Model) | 4000 |  |  | V |  |
| CDM | ESD Protection (Charged Device Model) | 2000 |  |  | V |  |
| LU | Latch-Up Immunity | 200 |  |  | mA |  |
| $\mathrm{C}_{\text {IN }}$ |  |  | 4.0 |  | pF | Inputs |
| $\theta_{\text {JA }}$ | Thermal Resistance Junction to Ambient JESD 51-3, single layer test board <br> JESD 51-6, 2S2P multilayer test board |  | $\begin{aligned} & 83.1 \\ & 73.3 \\ & 68.9 \\ & 63.8 \\ & 57.4 \\ & 59.0 \\ & 54.4 \\ & 52.5 \\ & 50.4 \\ & 47.8 \end{aligned}$ | $\begin{aligned} & 86.0 \\ & 75.4 \\ & 70.9 \\ & 65.3 \\ & 59.6 \\ & 60.6 \\ & 55.7 \\ & 53.8 \\ & 51.5 \\ & 48.8 \end{aligned}$ | $\begin{aligned} & { }^{\circ} \mathrm{C} / \mathrm{W} \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \\ & \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \end{aligned}$ | Natural convection <br> $100 \mathrm{ft} / \mathrm{min}$ <br> $200 \mathrm{ft} / \mathrm{min}$ <br> $400 \mathrm{ft} / \mathrm{min}$ <br> $800 \mathrm{ft} / \mathrm{min}$ <br> Natural convection <br> $100 \mathrm{ft} / \mathrm{min}$ <br> $200 \mathrm{ft} / \mathrm{min}$ <br> $400 \mathrm{ft} / \mathrm{min}$ <br> $800 \mathrm{ft} / \mathrm{min}$ |
| $\theta_{\text {Jc }}$ | Thermal Resistance Junction to Case |  | 23.0 | 26.3 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | MIL-SPEC 883E <br> Method 1012.1 |
|  | Operating Junction Temperature ${ }^{(2)}$ <br> (continuous operation) <br> MTBF = 9.1 years | 0 |  | 110 | ${ }^{\circ} \mathrm{C}$ |  |

1. Output termination voltage $\mathrm{V}_{\mathrm{TT}}=0 \mathrm{~V}$ for $\mathrm{V}_{\mathrm{CC}}=2.5 \mathrm{~V}$ operation is supported but the power consumption of the device will increase.
2. Operating junction temperature impacts device life time. Maximum continuous operating junction temperature should be selected according to the application life time requirements (See application note AN1545 for more information). The device AC and DC parameters are specified up to $110^{\circ} \mathrm{C}$ junction temperature allowing the MC100ES6226 to be used in applications requiring industrial temperature range. It is recommended that users of the MC100ES6226 employ thermal modeling analysis to assist in applying the junction temperature specifications to their particular application.

Table 6. DC Characteristics $\left(\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V} \pm 5 \% \text { and } 2.5 \mathrm{~V} \pm 5 \%, \mathrm{~T}_{\mathrm{J}}=0^{\circ} \mathrm{C} \text { to }+110^{\circ} \mathrm{C}\right)^{(\mathbf{1})}$

| Symbol | Characteristics | Min | Typ | Max | Unit | Condition |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| LVCMOS Control Inputs ( $\overline{\mathrm{OE}}, \mathrm{FSELO}, \mathrm{FSEL1}, \mathrm{MR}$ ) |  |  |  |  |  |  |
| $\mathrm{V}_{\text {IL }}$ | Input Voltage Low $\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V}$ <br> $\mathrm{~V}_{\mathrm{CC}}=2.5 \mathrm{~V}$  |  |  | $\begin{aligned} & 0.8 \\ & 0.7 \end{aligned}$ | V |  |
| $\mathrm{V}_{\mathrm{IH}}$ | $\begin{array}{ll}\text { Input Voltage High } & \mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V} \\ & \mathrm{~V}_{\mathrm{CC}}=2.5 \mathrm{~V}\end{array}$ | $\begin{aligned} & 2.2 \\ & 1.7 \end{aligned}$ |  |  | V |  |
| $\mathrm{I}_{\text {IN }}$ | Input Current ${ }^{(2)}$ |  |  | $\pm 150$ | $\mu \mathrm{A}$ | $\mathrm{V}_{\text {IN }}=\mathrm{V}_{\mathrm{CC}}$ or $\mathrm{V}_{\text {IN }}=\mathrm{GND}$ |
| LVPECL Clock Inputs (CLK, $\overline{\text { CLK }})^{(3)}$ |  |  |  |  |  |  |
| $\mathrm{V}_{\text {PP }}$ | DC Differential Input Voltage ${ }^{(4)}$ | 0.1 |  | 1.3 | V | Differential operation |
| $\mathrm{V}_{\text {CMR }}$ | Differential Cross Point Voltage ${ }^{(5)}$ | 1.0 |  | $\mathrm{V}_{\text {CC }}-0.3$ | V | Differential operation |
| $\mathrm{V}_{\mathrm{IH}}$ | Input High Voltage | TBD |  | TBD |  |  |
| $\mathrm{V}_{\text {IL }}$ | Input Low Voltage | TBD |  | TBD |  |  |
| $\mathrm{I}_{\text {IN }}$ | Input Current |  |  | $\pm 150$ | $\mu \mathrm{A}$ | $\mathrm{V}_{\text {IN }}=\mathrm{TBD}$ or $\mathrm{V}_{\text {IN }}=\mathrm{TBD}$ |
| LVPECL Clock Outputs (QA[2:0], QB[2:0], QC[2:0]) |  |  |  |  |  |  |
| $\mathrm{V}_{\mathrm{OH}}$ | Output High Voltage | $\mathrm{V}_{C C}-1.1$ |  | $\mathrm{V}_{\text {CC }}-0.8$ | V | Termination $50 \Omega$ to $\mathrm{V}_{\mathrm{TT}}$ |
| $\mathrm{V}_{\text {OL }}$ | Output Low Voltage | $\mathrm{V}_{C C}-1.8$ |  | $\mathrm{V}_{\text {CC }}-1.4$ | V | Termination $50 \Omega$ to $\mathrm{V}_{\mathrm{TT}}$ |
| Supply Current |  |  |  |  |  |  |
| $\mathrm{I}_{\text {GND }}$ | Maximum Quiescent Supply Current without Output Termination Current |  | 65 | 110 | mA | GND pin |
| $\mathrm{I}_{\mathrm{Cc}}$ | Maximum Quiescent Supply Current with Output Termination Current |  | 325 | 400 | mA | All $\mathrm{V}_{\mathrm{CC}}$ pins |

1. AC characteristics are design targets and pending characterization.
2. Input have internal pullup/pulldown resistors which affect the input current.
3. Clock inputs driven by LVPECL compatible signals.
4. $\mathrm{V}_{\mathrm{PP}}$ is the minimum differential input voltage swing required to maintain AC characteristic.
5. $\mathrm{V}_{\text {CMR }}(\mathrm{DC})$ is the crosspoint of the differential input signal. Functional operation is obtained when the crosspoint is within the $\mathrm{V}_{\mathrm{CMR}}$ ( DC ) range and the input swing lies within the $\mathrm{V}_{\mathrm{PP}}$ (DC) specification.

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Table 7. AC Characteristics $\left(\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V} \pm 5 \% \text { and } 2.5 \mathrm{~V} \pm 5 \%, \mathrm{~T}_{\mathrm{J}}=0^{\circ} \mathrm{C} \text { to }+110^{\circ} \mathrm{C}\right)^{(\mathbf{1}),(\mathbf{2})}$

| Symbol | Characteristics | Min | Typ | Max | Unit | Condition |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{PP}}$ | Differential Input Voltage ${ }^{(3)}$ (peak-to-peak) | 0.2 | 0.3 | 1.3 | V |  |
| $\mathrm{V}_{\text {CMR }}$ | Differential Input Crosspoint Voltage ${ }^{(4)}$ | 1.0 |  | $\mathrm{V}_{\mathrm{CC}}-0.3$ | V |  |
| $\mathrm{V}_{\mathrm{X}, \text { OUT }}$ | Differential Output Crosspoint Voltage | $\mathrm{V}_{\mathrm{CC}}-1.45$ |  | $\mathrm{V}_{\mathrm{CC}}-1.1$ | V |  |
| $\mathrm{V}_{\mathrm{O}(\mathrm{P}-\mathrm{P})}$ | $\begin{array}{\|l\|} \hline \text { Differential Output Voltage (peak-to-peak) } \\ \mathrm{f}_{\mathrm{O}}<300 \mathrm{MHz} \\ \mathrm{f}_{\mathrm{O}}<1.5 \mathrm{GHz} \\ \mathrm{f}_{\mathrm{O}}<2.7 \mathrm{GHz} \end{array}$ | $\begin{gathered} 0.45 \\ 0.3 \\ \text { TBD } \end{gathered}$ | $\begin{aligned} & 0.72 \\ & 0.55 \\ & 0.37 \end{aligned}$ | $\begin{aligned} & 0.95 \\ & 0.95 \\ & 0.95 \end{aligned}$ | $\begin{aligned} & V \\ & V \\ & V \end{aligned}$ |  |
| $\mathrm{f}_{\text {CLK }}$ | Input Frequency | 0 |  | $3000{ }^{(5)}$ | MHz |  |
| $t_{\text {PD }}$ | Propagation Delay CLK to Qx[] | 475 | 500 | 800 | ps | Differential |
| $\mathrm{t}_{\text {sk(0) }}$ | Output-to-Output Skew (within QA[2:0]) <br>  (within QB[2:0]) <br> (within QC[2:0])  <br>  (within device) |  | $\begin{gathered} \hline 11 \\ 12 \\ 4 \end{gathered}$ | $\begin{aligned} & 25 \\ & 25 \\ & 20 \\ & 60 \end{aligned}$ | $\begin{aligned} & \mathrm{ps} \\ & \mathrm{ps} \\ & \mathrm{ps} \\ & \mathrm{ps} \end{aligned}$ | Differential |
| $\mathrm{t}_{\text {sk(PP) }}$ | Output-to-Output Skew (part-to-part) |  |  | 325 | ps | Differential |
| $\mathrm{t}_{\mathrm{JIT}(\mathrm{CC})}$ | $\begin{array}{rr}\text { Output Cycle-to-Cycle Jitter } & \text { RMS (1 } 1 \sigma) \\ \text { single frequency configuration } \\ \div 1 / \div 2 \text { frequency configuration }\end{array}$ |  |  | $\begin{aligned} & 1 \\ & 1 \end{aligned}$ | $\begin{aligned} & \text { ps } \\ & \text { ps } \end{aligned}$ | $\begin{aligned} & \text { FSEL0 }=\text { FSEL1 } \\ & \text { FSEL0 }=\text { FSEL1 } \end{aligned}$ |
| DCo | $\begin{array}{\|l\|l} \hline \text { Output Duty Cycle } & \begin{array}{l} \mathrm{Qx}=\div 1, \mathrm{f}_{\mathrm{O}}<300 \mathrm{MHz} \\ \mathrm{Qx}=\div 1, \mathrm{f}_{\mathrm{O}}>300 \mathrm{MHz} \\ \\ \\ \\ \mathrm{Qx}=\div 2, \mathrm{f}_{\mathrm{O}}<300 \mathrm{MHz} \\ \mathrm{Qx}=\div 2, \mathrm{f}_{\mathrm{O}}>300 \mathrm{MHz} \end{array} \end{array}$ | $\begin{gathered} \hline 48 \\ 45 \\ \\ 49 \\ 47.5 \end{gathered}$ | $\begin{aligned} & 50 \\ & 50 \\ & 50 \\ & 50 \end{aligned}$ | $\begin{gathered} \hline 52 \\ 55 \\ 51 \\ 52.5 \end{gathered}$ | $\begin{aligned} & \hline \% \\ & \% \\ & \% \\ & \% \end{aligned}$ | $D C_{\text {fref }}=50 \%$ |
| $\mathrm{t}_{\mathrm{r}}, \mathrm{t}_{\mathrm{f}}$ | Output Rise/Fall Time | 0.05 |  | 200 | ns | 20\% to 80\% |
| $\mathrm{t}_{\text {PDL }}{ }^{(6)}$ | Output Disable Time | $2.5 \cdot \mathrm{~T}+\mathrm{t}_{\text {PD }}$ |  | 4.5.T + t ${ }_{\text {PD }}$ | ns | T = CLK period |
| $\mathrm{t}_{\text {PLD }}{ }^{(7)}$ | Output Enable Time | $3 \cdot \mathrm{~T}+\mathrm{t}_{\text {PD }}$ |  | $5 \cdot \mathrm{~T}+\mathrm{t}_{\text {PD }}$ | ns | T = CLK period |

1. AC characteristics are design targets and pending characterization.
2. AC characteristics apply for parallel output termination of $50 \Omega$ to $\mathrm{V}_{\mathrm{TT}}$.
3. $\mathrm{V}_{\mathrm{PP}}$ is the minimum differential input voltage swing required to maintain AC characteristics including tpd and device-to-device skew.
4. $\mathrm{V}_{\mathrm{CMR}}(\mathrm{AC})$ is the crosspoint of the differential input signal. Normal $A C$ operation is obtained when the crosspoint is within the $\mathrm{V}_{\mathrm{CMR}}$ ( AC ) range and the input swing lies within the $\mathrm{V}_{P P}(\mathrm{AC})$ specification. Violation of $\mathrm{V}_{\mathrm{CMR}}(\mathrm{AC})$ or $\mathrm{V}_{\mathrm{PP}}(\mathrm{AC})$ impacts the device propagation delay, device and part-to-part skew.
5. The MC100ES6226 is fully operational up to 3.0 GHz and is characterized up to 2.7 GHz .
6. Propagation delay $\overline{\mathrm{OE}}$ deassertion to differential output disabled (differential low: true output low, complementary output high).
7. Propagation delay $\overline{\mathrm{OE}}$ assertion to output enabled (active).


Figure 3. MC100ES6226 Output Disable/Enable Timing


Figure 4. MC100ES6226 AC Test Reference

## APPLICATIONS INFORMATION

## Maintaining Lowest Device Skew

The MC100ES6226 guarantees low output-to-output bank skew of 35 ps and a part-to-part skew of max. TBD ps. To ensure low skew clock signals in the application, both outputs of any differential output pair need to be terminated identically, even if only one output is used. When fewer than all nine output pairs are used, identical termination of all output pairs within the output bank is recommended. If an entire output bank is not used, it is recommended to leave all of these outputs open and unterminated. This will reduce the device power consumption while maintaining minimum output skew.

## Power Supply Bypassing

The MC100ES6226 is a mixed analog/digital product. The differential architecture of the MC100ES6226 supports low noise signal operation at high frequencies. In order to maintain its superior signal quality, all $\mathrm{V}_{\mathrm{CC}}$ pins should be bypassed by
high-frequency ceramic capacitors connected to GND. If the spectral frequencies of the internally generated switching noise on the supply pins cross the series resonant point of an individual bypass capacitor, its overall impedance begins to look inductive and thus increases with increasing frequency. The parallel capacitor combination shown ensures that a low impedance path to ground exists for frequencies well above the noise bandwidth.


Figure 5. V cc Power Supply Bypass

PACKAGE DIMENSIONS


CASE 873A-03
ISSUE B
32-LEAD LQFP PACKAGE

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